

<b>Notice of References Cited</b>		Application/Control No. 10/631,928	Applicant(s)/Patent Under Reexamination TEOH ET AL.	
		Examiner Victor X. Nguyen	Art Unit 3734	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,454,780	09-2002	Wallace, Michael P.	606/151
*	C	US-6,344,048	02-2002	Chin et al.	606/200
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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